	In place of PTO-1449	U. S. DEPART PATENT AND		OF COMMERCE MARK OFFICE	Complete if Known		
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MAR MAR					Applicant(s) Art Unit	Wayne A. Weimer	
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TRA	EN BET	1	OF	1	Attorney Docket Number	34003.30	

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THM	AA	6,608,716	08-19-2003	Armstrong, et al.		
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Examiner's	V Cite ✓ No	Include name of the author (in CAPITAL LETTERS), title of the article, title of the litem, date, page(s), volume-
THM	AB	Kim, W., et al., "Fractals in Microcavities: Giant Coupled, Multiplicative Enhancement of Optical Responses", Physical Review Letters, Vol. 82, Issue 24, June 14, 1999, pp. 4811-4814.
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Signature			\wedge	Date	
Signature				Considered	12/15/01
	/	 		Considered	10/11/09

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.